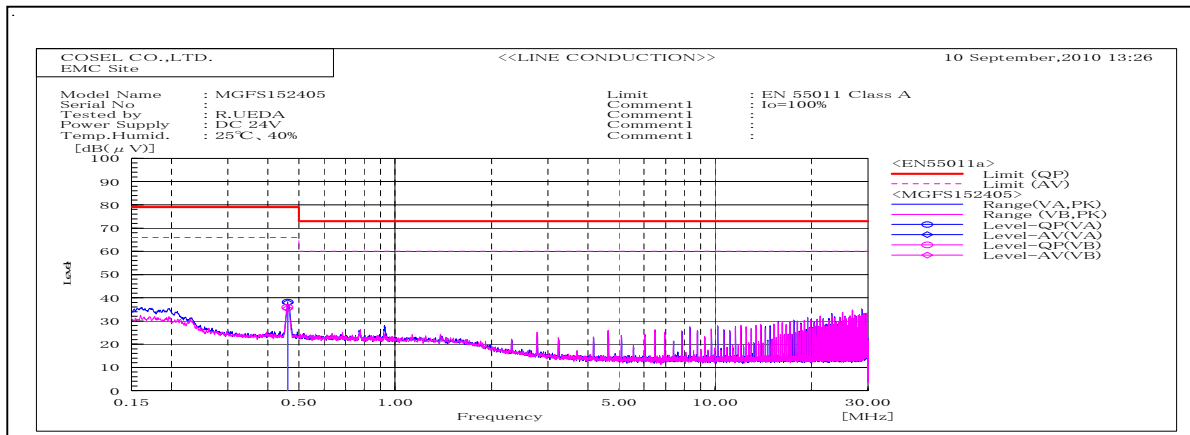
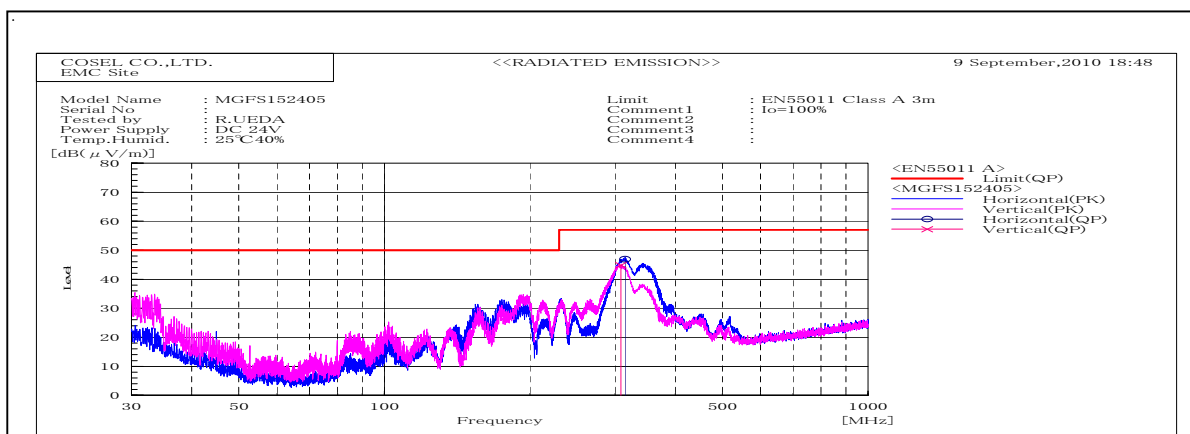


DATA SHEET		Date	21-Sep-10
Model	MGFS152405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46078		VB	26	25.3	10	36	35.3	79	66	43	30.7	Pass	
0.46181		VA	28.1	27.7	10.1	38.2	37.8	79	66	40.8	28.2	Pass	

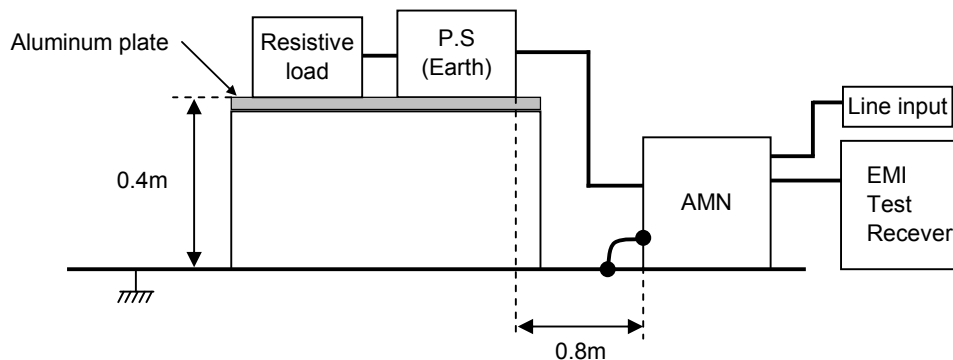


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
308.278	V	Stable	62.2		-17.4	44.8		57	12.2	Pass	136	125	
314.55	H	Stable	64.2		-17.3	46.9		57	10.1	Pass	102	27	

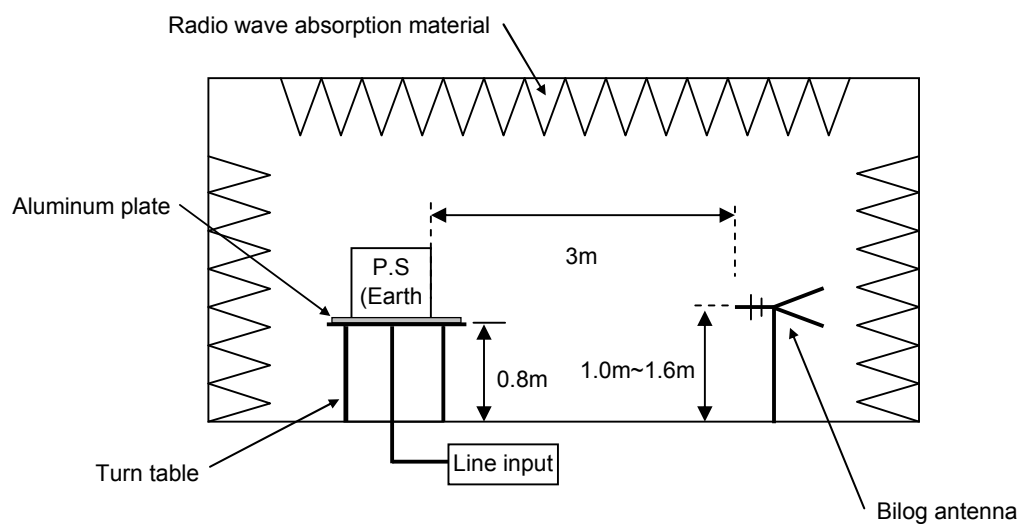
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

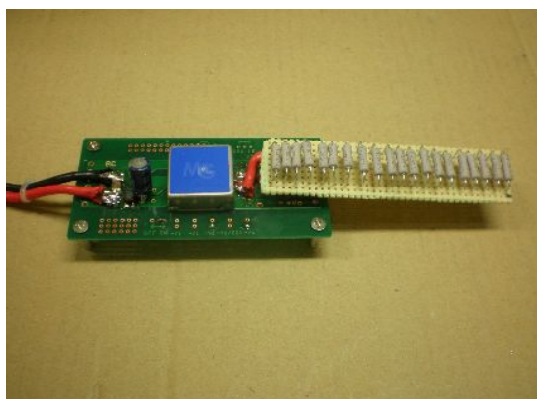


Conditions

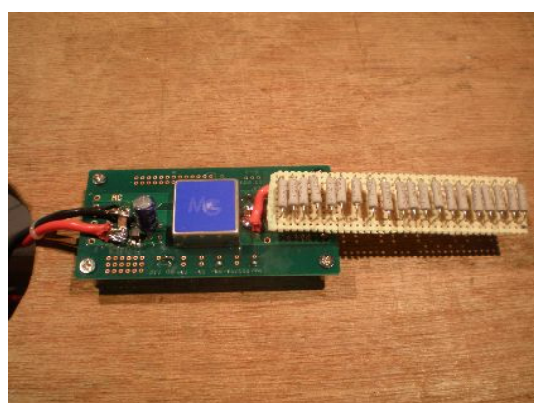
Test : EMI
Model Name : MGFS1524□□/MGFW1524□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

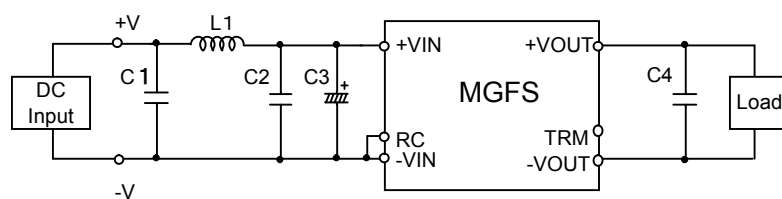


Fig.1 Testing circuitry 1

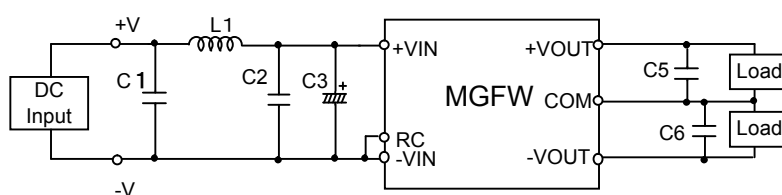


Fig.2 Testing circuitry 2

L1	:	0.5μH	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	:	50V 6.8 μ F	C4532X7R1H685MT	(TDK)
C3	:	50V 100 μ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 μ F	CM32X5R226K25A	(KYOCERA)